

XDS Process Analytics™ Direct Light



XDS Process Analytics™ Direct Light with measuring head

Features and Benefits

- Non destructive in-line analysis of moving product such as meat or cheese performed directly in the process line enables cost-effective quality control
- Quantitative and qualitative data for better in-line process control
- Superior analytical performance through inventive design keeps NIR calibration costs to a minimum and makes transferability possible
- The measuring head comes in two designs, one for dusty environments and one for environments with high demands on hygiene which makes it possible to use in different working environments

Description

The XDS Process Analytics™ Direct Light is a new generation of the well known instrument for rapid non-destructive analysis of slurries, solid or semi solid food and agricultural products. The solution can help you control a number of parameters in your

production in a simple way. It is easy to install and integrate. The solution is a non-contact measurement system providing in-line analysis based on NIR (Near Infrared Spectroscopy).

Precise instrument matching enhances method development, minimizes implementation and ensures calibration model transferability between instruments.

System Description

The measuring head is attached in the terminal end of an optical fiber. A high-intensity light source contained in the sensor head illuminates the sample brightly enough to minimize ambient light effects. Light interacts with the sample and is reflected back to the sensor head, picked up by the collection fiber, and passed on to the instrument for dispersions and signal detection. The configuration provides measurements at one sampling point.

Specifications

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| Analysis time: | Approximately one analysis every 15 – 20 seconds |
| Measurement mode: | Reflectance |
| Wavelength range: | 800 – 2200 nm |
| Detector: | Extended InGaAs |
| Software package: | FOSS analyser SW, Vision or ISIScan™ |
| Spectral resolution: | 0.5 nm |
| Wavelength accuracy: | <0.08 nm |
| Wavelength precision: | (SD) < 0.004 nm |
| Noise: | < 100 micro AU |

Standards and Approvals

XDS Process Analytics™ Direct Light is CE labeled and complies with the following directives:

- EMC (Electro Magnetic Compatibility) Directive 2004/108/EC
- LVD (Low Voltage Directive) 2006/95/EC
- Packing and Waste Directive 94/62/EC
- RoHS Directive 2002/95/ec

Installation Requirements

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| Power supply: | Recommended isolated or conditioned line power: 100 – 240 VAC 50 – 60 Hz, 1 A, max 300W |
| Operating temperature: | Basic config.: 5 – 35°C (40 – 95°F) |
| Ambient humidity: | 10 – 90% relative |
| Weight: | 42.2 kg/93 lbs |
| Dimensions (W × D × H): | 457 × 572 × 387 mm / 19 × 24 × 14 inches |
| Enclosure: | Basic unit IP65/NEMA 4x stainless steel, Measuring head IP69K stainless steel A basic unit enclosure IP69K is available for humid environments |
| Process communication: | Options for OPC, Modbus; Profibus etc |
| NIR standard kit is included for hardware standardization | |

FOSS

FOSS Analytical
Slangerupgade 69
DK-3400 Hilleroed
Denmark

Tel.: +45 7010 3370
Fax: +45 7010 3371

info@foss.dk
www.foss.dk

